TOF-SIMS Data Reduction Software

TOF-DR 3.0 is the latest release of PHI's software for the treatment, processing, presentation and reporting of TOF-SIMS tandem MS imaging data.

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The new release includes new or improved capabilities for instant viewing of raw data, peak identification, graphical data presentation and report generation.

- Windows 10 64-bit compatibility
- TOF-SIMS MS/MS spectra and 2D/3D image analysis
- Spectral dead time correction
- 2D/3D region-of-interest (ROI) analysis

Division of

- Software-guided batch data processing with output to Excel® for plotting and graphical viewing of the raw and normalized data
- Data Review Utility tool for instant and simultaneous observation of peaks, images and profiles with identification tools
- Report Generation tool for easy layout and presentation of data with automated creation of PowerPoint® slides
- PLS_Toolbox® compatibility for full uni- and multi-variate data analysis
- NIST MS/MS® compatibility for tandem MS precursor identification.



Data Export & Report Generation Tool



Software-Guided Batch Data Processing



3D image of a corrosion defect in glass

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Review Utility and Peak Identification

Review Tool

Software-guided batch data processing steps the analyst from selection of the data files, through selection of the peaks of interest and spectral calibration, to output of the normalized peak data to an Excel® spreadsheet where the data may be plotted and graphed.

The data Review Utility enables instant viewing of raw TOF-SIMS and tandem MS spectral, image and profile data in a simultaneous fashion with built-in features for TOF-SIMS peak identification. The NIST MS/MS® Reference Library is used for tandem MS precursor identification.

The Report Generation tool allows the analyst to layout spectral, image and/or profile data in a single page, with full scaling capabilities, with automated creation of an associated PPT® slide.

The PHI raw data files are fully compatible with PLS_Toolbox so that the analyst can perform statistical analysis, univariate or multivariate treatment of the spectral and image data.

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